

GB100XCP12-227

IGBT/SiC Diode Co-pack

 V_{CES} = 1200 V I_{CM} = 100 A $V_{CE(SAT)}$ = 1.9 V

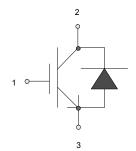
Features

- Optimal Punch Through (OPT) technology
- SiC freewheeling diode
- Positive temperature coefficient for easy paralleling
- Extremely fast switching speeds
- Temperature independent switching behavior of SiC rectifier
- Best RBSOA/SCSOA capability in the industry
- · High junction temperature
- · Industry standard packaging

Package

• RoHS Compliant





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Advantages

- · Industry's highest switching speeds
- High temperature operation
- Improved circuit efficiency
- · Low switching losses

Applications

- Solar Inverters
- Aerospace Actuators
- Server Power Supplies
- Resonant Inverters > 100 kHz
- · Inductive Heating
- Electronic Welders

Maximum Ratings at T_i = 175 °C, unless otherwise specified

Parameter	Symbol	Conditions	Values	Unit	
IGBT					
Collector-Emitter Voltage	V _{CES}		1200	V	
DC-Collector Current	Ic	T _C ≤ 130 °C	100	Α	
Peak Collector Current			200	Α	
Gate Emitter Peak Voltage	$V_{\sf GES}$		± 20	V	
IGBT Short Circuit SOA	t_psc	$V_{CC} = 900 \text{ V, } V_{CEM} \le 1200 \text{ V}$ $V_{GE} \le 15 \text{ V, } T_{V_i} \le 125 \text{ °C}$		μs	
Operating Temperature	T _{vi}		-40 to +175	°C	
Storage Temperature	T _{stg}		-40 to +175	°C	
Isolation Voltage	V_{ISOL}	I_{SOL} < 1 mA, 50/60 Hz, t = 1 s	3000	V	
Free-wheeling Silicon Carbide diode					
DC-Forward Current	I _F	T _C ≤ 130 °C	100	Α	
Non Repetitive Peak Forward Current	I _{FM}	$T_C = 25 ^{\circ}\text{C}, t_P = 10 \mu\text{s}$	tbd	Α	
Surge Non Repetitive Forward Current	$I_{F,SM}$	t_P = 10 ms, half sine, T_C = 25 °C	tbd	Α	
Thermal Characteristics					
Thermal resistance, junction - case	R _{thJC}	IGBT	0.08	°C/W	
Thermal resistance, junction - case	R _{thJC}	SiC Diode	0.53	°C/W	

Machanical Dranautica		Values			
Mechanical Properties		min.	typ.	max.	
Mounting Torque	M_d		1.5		Nm
Terminal Connection Torque		1.3		1.5	Nm
Weight			29		g
Case Color		Black			
Dimensions		38 x 25.4 x 12 mm			mm

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Electrical Characteristics at T_i = 175 °C, unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
r ai ailletei	Syllibol	Conditions	min.	typ. max.		Unit
IGBT						
Gate Threshold Voltage	$V_{GE(th)}$	$V_{GE} = V_{CE}, I_{C} = 4 \text{ mA}, T_{j} = 25 ^{\circ}\text{C}$	5	6.2	7	V
Collector Emitter Leakage Current	I _{CES,25}	V _{GE} = 0 V, V _{CE} = V _{CES} , T _j = 25 °C		0.10	1	mA
Collector-Emitter Leakage Current	I _{CES,175}	V _{GE} = 0 V, V _{CE} = V _{CES} , T _j = 175 °C		3.15		mA
Gate-Leakage Current	I_{GES}	$V_{CE} = 0 \text{ V}, V_{GE} = 20 \text{ V}, T_j = 175 ^{\circ}\text{C}$	-400		400	nA
Collector-Emitter Threshold Voltage	V _{CE(TO)}	T _j = 25°C		1.1		V
Callanter Freitter Clara Basistana	R _{CE,25}	V _{GE} = 15 V, T _j = 25 °C		7.9		mΩ
Collector-Emitter Slope Resistance	R _{CE,175}	V _{GE} = 15 V, T _j = 175 °C		11.4		mΩ
Collector-Emitter Saturation Voltage	$V_{\text{CE(SAT)}}$	$I_C = 100 \text{ A}, V_{GE} = 15 \text{ V},$ $T_i = 25 ^{\circ}\text{C} (175 ^{\circ}\text{C})$		1.9 (2.2)		V
Input Capacitance	C_{ies}	V = 0.V V = 0.E.V		8.55		nF
Output Capacitance	C _{oes}	$V_{GE} = 0 \text{ V}, V_{CE} = 25 \text{ V},$ $f = 1 \text{ MHz}, T_i = 150 ^{\circ}\text{C}$		1.39		nF
Reverse Transfer Capacitance	C_{res}			0.25		nF
Internal Gate Resistance	R _{Gint}			2		Ω
Gate Charge	Q_{G}	V _{CC} = 750 V, I _C = 100 A, V _{GE} = -815 V, T _i = 25 °C (125 °C)		900 (900)		nC
Module Lead Resistance	R _{mod}	T _c = 25 °C (175 °C)		tbd		mΩ
Reverse Bias Safe Operating Area	RBSOA	T_j =175 °C, R_g =56 Ω , V_{CC} =1200 V, V_{GF} =15 V		150		Α
Short Circuit Current	I _{sc}	$T_i = 175 ^{\circ}\text{C}, R_g = 56\Omega, V_{CC} = 900 \text{V},$		470		Α
Short Circuit Duration	t _{sc}	V _{GE} = ±15 V			10	μs
Rise Time	t _r	1		254		ns
Fall Time	t _f	V = 800 V I = 100 A		153		ns
Turn On Delay Time	t _{d(on)}	V_{CC} = 800 V, I_{C} = 100 A, R_{gon} = R_{goff} = 10 Ω ,		244		ns
Turn Off Delay Time	t _{d(off)}	V _{GE(on)} = 15 V, V _{GE(off)} = -8 V,		488		ns
Turn-On Energy Loss Per Pulse	E _{on}	L _S = 0.8 μH, T _j = 25 °C		14.2		mJ
Turn-Off Energy Loss Per Pulse	E _{off}	†		15.7		mJ
Rise Time	t _r			211		ns
Fall Time	t _f	V _{CC} = 800 V, I _C = 100 A,		172		ns
Turn On Delay Time	t _{d(on)}	$R_{\text{gon}} = R_{\text{goff}} = 100 \text{ A},$		240		ns
Turn Off Delay Time	t _{d(off)}	VGE(on)= 15 V, V _{GE(off)} = -8 V,		636		ns
Turn-On Energy Loss Per Pulse	E _{on}	L _S = 0.8 μH, T _j = 175 °C		11.1		mJ
Turn-Off Energy Loss Per Pulse	E _{off}			21.8		mJ
Free-wheeling Silicon Carbide Diode	-					
Forward Voltage	V_{F}	I _F = 100 A, V _{GE} = 0 V, T _j = 25 °C (175 °C)		2.08 (3.5)		V
Threshold Voltage at Diode	$V_{D(TO)}$	T _j = 25 °C		0.8		V
Peak Reverse Recovery Current	I _{rrm}	I _F = 100 A, V _{GE} = 0 V, V _R = 800 V,		10		Α
Reverse Recovery Time	t _{rr}	-dI _F /dt = 625 A/µs, T _j = 175 °C		100		ns
Rise Time	t _r	V _{CC} = 800 V, I _C = 100 A,		148		ns
Fall Time	t _f	$R_{\text{gon}} = R_{\text{goff}} = 100 \Omega,$		336		ns
Turn-On Energy Loss Per Pulse	E _{on}	_{VGE(on)} = 15 V, V _{GE(off)} = -8 V,		218		μJ
Turn-Off Energy Loss Per Pulse	E _{off}	L _S = 0.8 μH, T _j = 25 °C		113		μJ
Reverse Recovery Charge	Q _{rr}			730		nC
Rise Time	t _r	.,		178		ns
Fall Time	t _f	$V_{CC} = 800 \text{ V}, I_C = 100 \text{ A},$		268		ns
Turn-On Energy Loss Per Pulse	E _{on}	$R_{gon} = R_{goff} = 10 \Omega,$ $V_{GE(on)} = 15 V, V_{GE(off)} = -8 V,$		23		μJ
Turn-Off Energy Loss Per Pulse	E _{off}	$L_{\rm S} = 0.8 \mu H, T_{\rm i} = 175 ^{\circ} C$		334		μJ
Reverse Recovery Charge	Q_{rr}	_ , , ,		480		nC



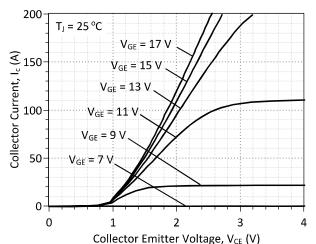


Figure 1: Typical Output Characteristics at 25 °C

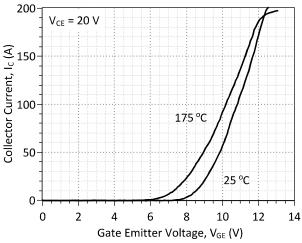


Figure 3: Typical Transfer Characteristics

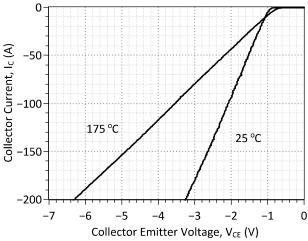


Figure 5: Typical FWD Forward Characteristics

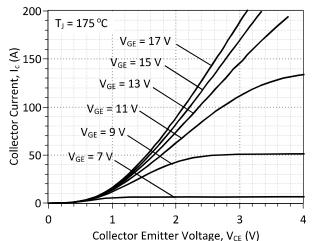


Figure 2: Typical Output Characteristics at 175 °C

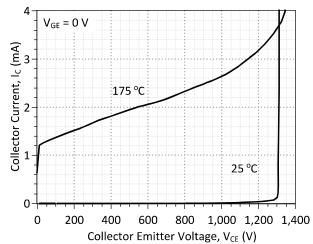


Figure 4: Typical Blocking Characteristics

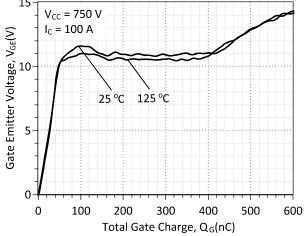


Figure 6: Typical Turn On Gate Charge



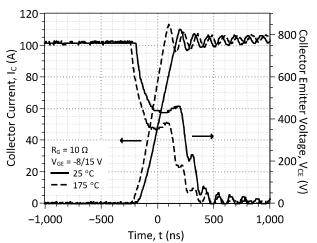


Figure 7: Typical Hard-Switched IGBT Turn On Waveforms

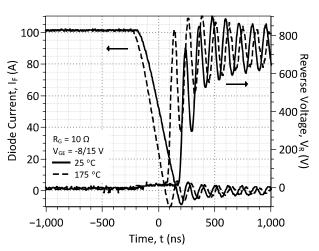


Figure 9: Typical Hard-Switched Free-wheeling SiC Diode Turn Off Waveforms

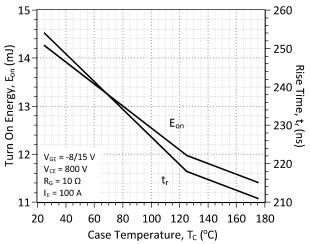


Figure 11: Typical Module Energy Losses and Switching Times at IGBT Turn On vs. Temperature

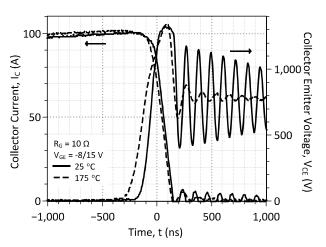


Figure 8: Typical Hard-Switched IGBT Turn Off Waveforms

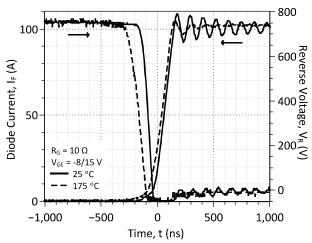


Figure 10: Typical Hard-Switched Free-wheeling SiC Diode Turn On Waveforms

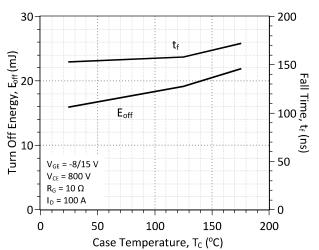


Figure 12: Typical Module Energy Losses and Switching Times at IGBT Turn Off vs. Temperature



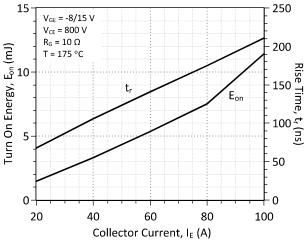


Figure 13: Typical Module Energy Losses and Switching Times at IGBT Turn On vs. Current

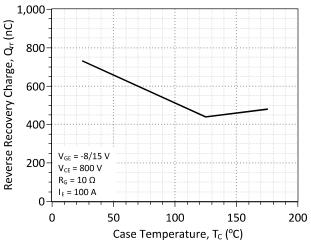


Figure 15: Typical Hard-Switched Reverse Recovery Charge vs. Temperature

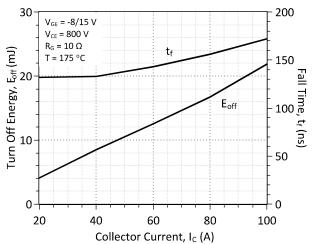


Figure 14: Typical Module Energy Losses and Switching Times at IGBT Turn Off vs. Current

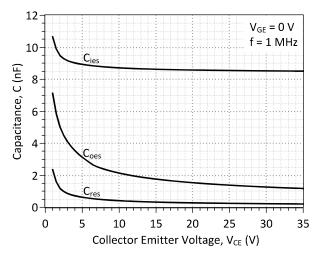


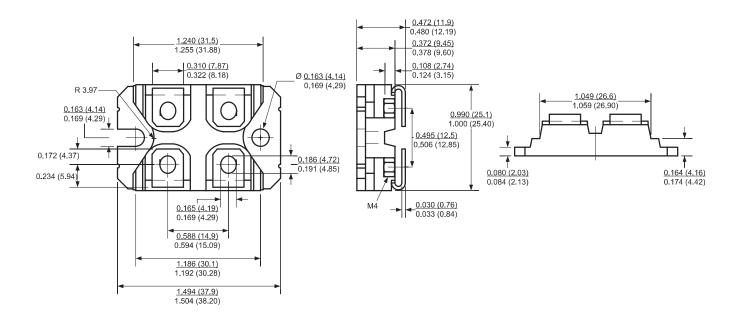
Figure 16: Typical C-V Characteristics



Package Dimensions:

SOT-227

PACKAGE OUTLINE



NOTE

- 1. CONTROLLED DIMENSION IS INCH. DIMENSION IN BRACKET IS MILLIMETER.
- 2. DIMENSIONS DO NOT INCLUDE END FLASH, MOLD FLASH, MATERIAL PROTRUSIONS

	Revision History						
Date		Revision	Comments	Supersedes			
ſ	2013/02/08	2	Updated Electrical Characteristics				
ſ	2012/07/30	1	Second generation release	GA100XCP12-227			
ſ	2011/01/06	0	Initial release				
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